- Compares Two 8-Bit Words
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

description

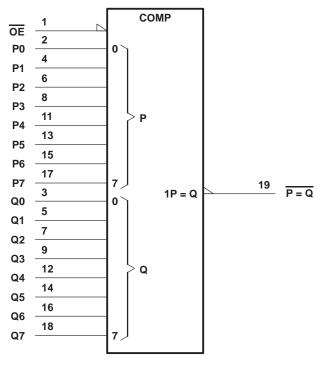
These identity comparators perform comparisons on two 8-bit binary or BCD words. They provide $\overline{P} = Q$ outputs.

The SN54F521 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74F521 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

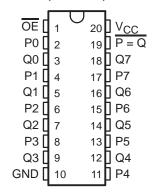
INPL	JTS	OUTPUT
P, Q	OE	P = Q
P = Q	L	L
P≠Q	Χ	Н
Х	Н	Н

logic symbol†

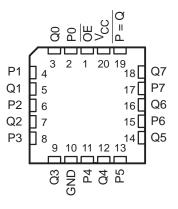


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN54F521 . . . J PACKAGE SN74F521 . . . DW OR N PACKAGE (TOP VIEW)

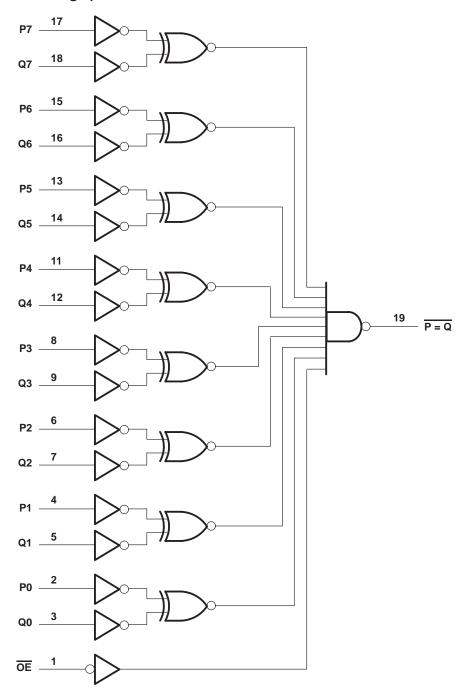


SN54F521 . . . FK PACKAGE (TOP VIEW)





logic diagram (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	–1.2 V to 7 V
Input current range	–30 mA to 5 mA
Voltage range applied to any output in the high state	0.5 V to V _{CC}
Current into any output in the low state	40 mÅ
Operating free-air temperature range: SN54F521 .	–55°C to 125°C
SN74F521 .	0°C to 70°C
Storage temperature range	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54F521			SN74F521			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNII
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.8			0.8	V
lιΚ	Input clamp current			-18			-18	mA
ІОН	High-level output current			- 1			- 1	mA
l _{OL}	Low-level output current			20			20	mA
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		S	SN54F521			SN74F521		
			MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIK	$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V
V0.1	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -1 \text{ mA}$	2.5	3.4		2.5	3.4		V
VOH	$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -1 \text{ mA}$				2.7			
VOL	V _{CC} = 4.5 V,	$I_{OL} = 20 \text{ mA}$		0.3	0.5		0.3	0.5	V
lį	$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			100			100	μΑ
lіН	$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20			20	μΑ
I _Ι Γ	V _{CC} = 5.5 V,	V _I = 0.5 V			- 0.6			- 0.6	mA
I _{OS} §	V _{CC} = 5.5 V,	V _O = 0	-60		-150	-60		-150	mA
ICC	V _{CC} = 5.5 V,	See Note 2		21	32		21	32	mA

 $[\]ddagger$ All typical values are at V_{CC} = 5 V, T_A = 25°C.

NOTE 2: ICC is measured with all inputs at 4.5 V.

NOTE 1: The input voltage ratings may be exceeded provided the input current ratings are observed.

[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

SN54F521, SN74F521 8-BIT IDENTITY COMPARATORS

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switching characteristics (see Note 3)

PARAMETER	FROM (INPUT)	то (оитрит)	$V_{CC} = 5 \text{ V},$ $C_{L} = 50 \text{ pF},$ $R_{L} = 500 \Omega,$ $T_{A} = 25^{\circ}\text{C}$			V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω , T_A = MIN to MAX [†]				UNIT
			′F521		SN54F521		SN74F521			
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
^t PLH	P or Q	P = Q	2.7	6.6	10	2.7	14	2.7	11	ns
t _{PHL}	FUIQ		3.7	6.6	10	3.2	12	3.2	11	1115
^t PLH	ŌĒ	P = Q	2.2	4.6	6.5	2.2	8.5	2.2	7.5	ns
^t PHL	OL		2.7	6.1	9	2.7	13.5	2.7	10	115

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 3: Load circuits and waveforms are shown in Section 1.



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